

<b>Notice of References Cited</b>	Application/Control No. 10/665,529	Applicant(s)/Patent Under Reexamination YAMAUCHI ET AL.	
	Examiner Pawandeep S. Dhingra	Art Unit 2625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,765,082 A	06-1998	Numazu et al.	399/299
*	B	US-6,108,510 A	08-2000	Nakane, Eiji	399/303
*	C	US-6,314,255 B1	11-2001	Yokomori et al.	399/119
*	D	US-6,324,374 B1	11-2001	Sasamoto et al.	399/298
*	E	US-6,356,732 B1	03-2002	Watanabe et al.	399/299
*	F	US-6,470,166 B2	10-2002	Mizoguchi et al.	399/302
*	G	US-6,546,218 B2	04-2003	Uchida, Michio	399/167
*	H	US-6,636,711 B1	10-2003	Katahira, Shunsuke	399/82
*	I	US-6,731,895 B2	05-2004	Hamada et al.	399/121
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09-292753	11-1997	JAPAN	Hamada Futoshi	G03G 15/01
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.